Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,526	HIDAKA ET AL.	
Examiner	Art Unit	
Dennis Myint	2162	

SEARCHED					
Class	Subclass	Date	Examiner		
707	3	2/27/2007	DM		
715	513	2/28/2007	ÞМ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
-	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	2/27/2007	DM		
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	2/28/2007	DM		
NPL: GOOGLE	2/28/2007	DM		
NPL: IEEE	2/28/2007	DM		